



4/13/2009

RELIABILITY MONITOR REPORT  
FOR

**TSMC 0.5 $\mu$ m Silicon Gate CMOS**

**MAXIM Integrated Products**

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Sunnyvale, CA 94086

This Report was prepared by  
Maxim Reliability Engineering

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

LMX331AUK+	MAX6902ETA
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The calculated failure rate for devices using this process is:

**FAILURE RATE:**                      **MTTF (YRS): 17095**                      **FITS: 6.7**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%**                      **Ea: 0.7**                      **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2007 and 9/30/2008 .

**Process Information:**

Process Description:                      TSMC 0.5µm Silicon Gate CMOS

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0712	LMX331AUK+	135C	1000 HRS	80	0	K080BA004F#
HIGH TEMP OP LIFE	0735	MAX6902ETA	135C	192 HRS	55	0	K2F0DA025BQ
<b>Total:</b>						<b>0</b>	

**STORAGE LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0712	LMX331AUK+	150C	1000 HRS	80	0	K080BA004F#
<b>Total:</b>						<b>0</b>	

**TEMPERATURE HUMIDITY BIAS**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
BIASED MOISTURE	0712	LMX331AUK+	130C, 85% R.H.	96 HRS	77	0	K080BA004F#
<b>Total:</b>						<b>0</b>	

**FAILURE RATE:**                      **MTTF (YRS): 17095**                      **FITS: 6.7**